INFO	ORMATION CITATION		ATTY. DOCKET NO. 2336-257		U.S. PATENT APPLICATION NO. 10/811,808			
	APPLICA	ATION nor	0 5 2005 S	APPLICANT Seung Wan CHAE et al.				
	(PTO-1	13	FILING DATE March 30, 2004		GROUP 2814			
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V	08-032115	2/1996		Japan			X	
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PENE	ORMATION :	ATTY. DOCKET NO. 2336-257		U.S. PATENT APPLICATION NO. 10/811,808				
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